

PCTEST ENGINEERING LABORATORY, INC.

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HEARING AID COMPATIBILITY

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do 16677, Korea Date of Testing: 4/08/2018 - 4/10/2018 Test Site/Location: PCTEST Lab, Columbia, MD, USA Test Report Serial No.: 1M1804160074-01-R1.A3L

FCC ID:

A3LSMJ337T

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

Scope of Test: Application Type: FCC Rule Part(s): HAC Standard:	Audio Band Magnetic Testing (T-Coil) Class II Permissive Change CFR §20.19(b) ANSI C63.19-2011 285076 D01 HAC Guidance v05 285076 D02 T-Coil testing for CMRS IP v03
DUT Type:	Portable Handset
Model:	SM-J337T
Additional Model(s):	SM-S357BL
Test Device Serial No.:	<i>Pre-Production Sample</i> [S/N: 11912]
Class II Permissive Change(s):	GSM Voice audio parameter software change
Original Grant Date:	4/5/2018

C63.19-2011 HAC Category:

T3 (SIGNAL TO NOISE CATEGORY)

Note: This revised Test Report (S/N: 1M1804160074-01-R1.A3L) supersedes and replaces the previously issued test report on the same subject device for the same type of testing as indicated. Please discard or destroy the previously issued test report(s) and dispose of it accordingly.

This report pertains to the GSM modes supported by the device. Please refer to the HAC T-coil report (S/N: 1M1802070017-02-R2.A3L) for the original compliance evaluation and overall HAC category rating. This wireless portable device has been shown to be hearing-aid compatible for GSM air interfaces, under the above rated category, specified in ANSI/IEEE Std. C63.19-2011 and has been tested in accordance with the specified measurement procedures. Test results reported herein relate only to the item(s) tested. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report. North American Bands only.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Randy Ortanez President



01/11/2018

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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide and 30 million people in the United States suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1-1 Hearing Aid *in-vitu*

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

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2. DUT DESCRIPTION



A3LSMJ337T
Samsung Electronics Co., Ltd.
129, Samsung-ro, Maetan dong,
Yeongtong-gu, Suwon-si
Gyeonggi-do 16677, Korea
SM-J337T
SM-S357BL
11912
REV0.7
J337T.001
Internal Antenna
Portable Handset

Table 2-1 SM-J337T HAC Air Interfaces

Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service
	850	vo	Yes ¹	Yes: WIFI or BT	CMRS Voice*
GSM	1900	vo	Yes	Tes. WIFI OF BT	
	GPRS/EDGE	VD	No ¹	Yes: WIFI or BT	Google Duo**
	850				
UMTS	1700	VD	No ¹	Yes: WIFI or BT	CMRS Voice*
UIVITS	1900				
	HSPA	VD	No ¹	Yes: WIFI or BT	Google Duo**
	680 (B71)		No ¹		
	700 (B12)		1		
	850 (B5)				
LTE (FDD)	1700 (B4)	VD		1	Yes: WIFI or BT
	1700 (B66)		No ¹		
	1900 (B2)				
	2500 (B7)				
WIFI	2450	VD	No ¹	Yes: GSM, UMTS, or LTE	VoWIFI**, Google Duo**
BT	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A
Type Transport Notes: VO = Voice Only * Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE DT = Digital Data - Not intended for CMRS Service * Reference level is -20dBm0 in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE VD = CMRS and IP Voice over Data Transport ** Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 1. This report only pertains to GSM voice services. Please refer to the original certification te report (S/N: 1M1802070017-02-R2.A3L) for data on other modes supported by this device.			, 5076 D02 to the original certification technica		

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Air-Interface	Band (MHz)	Type Transport	HAC Tested	Simultaneous But Not Tested	Name of Voice Service																		
	850	vo	Yes	Yes: WIFI or BT	CMRS Voice*																		
GSM	1900		105																				
	GPRS/EDGE	VD	No ¹	Yes: WIFI or BT	Google Duo**																		
	850																						
UMTS	1700	VD	No ¹	Yes: WIFI or BT	CMRS Voice*																		
UIVITS	1900																						
	HSPA	VD	No ¹	Yes: WIFI or BT	Google Duo**																		
	680 (B71)		No ¹																				
	700 (B12)																						
()	850 (B5)		No ¹	No ¹	No ¹	No ¹	No ¹	No ¹	No ¹	No ¹	No ¹												
LTE (FDD)	1700 (B4)	VD VD										No ¹	Yes: WIFI or BT	VoLTE*, Google Duo**									
	1700 (B66)																						
	1900 (B2)																						
WIFI	2450	VD	No ¹	Yes: GSM, UMTS, or LTE	VoWIFI**, Google Duo**																		
BT	2450	DT	No	Yes: GSM, UMTS, or LTE	N/A																		
Type Transport VO = Voice Only DT = Digital Data - Not intended for CMRS Service VD = CMRS and IP Voice over Data Transport VD = CMRS and IP Voice over Data Transport VD = CMRS and IP Voice over Data Transport Notes: * Reference level in accordance with 7.4.2.1 of ANSI C63.19-2011 and July 2012 C63 VoLTE Interpretation. ** Reference level is -20dBm0 in accordance with FCC KDB 285076 D02 1. This report only pertains to GSM voice services. Please refer to the original certification tereport(S/N: 1M1802070017-02-R2.A3L) for data on other modes supported by this device.			5076 D02 to the original certification technic																				

Table 2-2 SM-S357BL HAC Air Interfaces

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3. ANSI C63.19-2011 PERFORMANCE CATEGORIES

I. MAGNETIC COUPLING

Axial and Radial Field Intensity

All orientations of the magnetic field, in the axial and radial position along the measurement plane shall be \geq -18 dB(A/m) at 1 kHz in a 1/3 octave band filter per §8.3.1.

Frequency Response

The frequency response of the axial component of the magnetic field shall follow the response curve specified in EIA RS-504-1983, over the frequency range 300 Hz – 3000 Hz per §8.3.2.

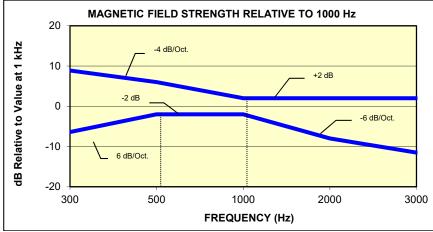
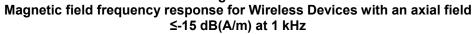


Figure 3-1



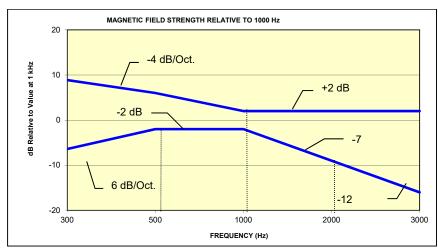


Figure 3-2

Magnetic Field frequency response for wireless devices with an axial field that exceeds -15 dB(A/m) at 1 kHz

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Signal Quality

The table below provides the signal quality requirement for the intended audio magnetic signal from a wireless device. Only the RF immunity of the hearing aid is measured in T-coil mode. It is assumed that a hearing aid can have no immunity to an interference signal in the audio band, which is the intended reception band for this mode. The only criterion that can be measured is the RF immunity in T-coil mode. This is measured using the same procedure as the audio coupling mode at the same levels.

The signal quality of the axial and radial components of the magnetic field was used to determine the T-coil mode category.

Category	Telephone RF Parameters		
	Wireless Device Signal Quality [(Signal + Noise)-to-noise ratio in dB]		
T1	0 to 10 dB		
T2	10 to 20 dB		
Т3	20 to 30 dB		
T4	> 30 dB		
Table 3-1 Magnetic Coupling Parameters			

Note: The FCC limit for SNNR is 20dB and the test data margins will indicate a margin from the FCC limit for compliance.

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4. METHOD OF MEASUREMENT

I. Test Setup

The equipment was connected as shown in an acoustic/RF hemi-anechoic chamber:

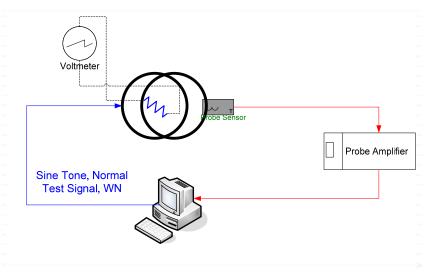
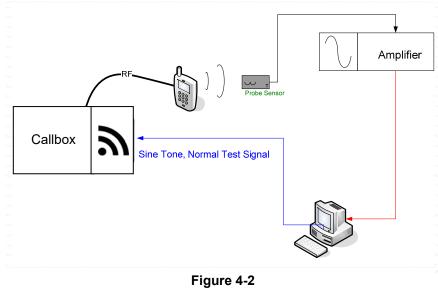


Figure 4-1 Validation Setup with Helmholtz Coil



T-Coil Test Setup

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II. Scanning Mechanism

Manufacturer:	TEM
Accuracy:	± 0.83 cm/meter
Minimum Step Size:	0.1 mm
Maximum speed	6.1 cm/sec
Line Voltage:	115 VAC
Line Frequency:	60 Hz
Material Composite:	Delrin (Acetal)
Data Control:	Parallel Port
Dynamic Range (X-Y-Z):	45 x 31.75 x 47 cm
Dimensions:	36" x 25" x 38"
Operating Area:	36" x 49" x 55"
Reflections:	< -20 dB (in anechoic chamber)

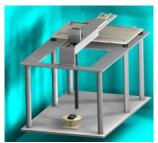


Figure 4-3 RF Near-Field Scanner

III. 3GPP2 Normal Test Signal (Speech)

Manufacturer:	3GPP2 (TIA 1042 §3.3.1)
	Modified-IRS weighted, multi-talker speech signal, 4 Male and 4
Stimulus Type:	Female speakers (alternating)
Single Sample Duration:	51.62 seconds
Activity Level:	77.4%

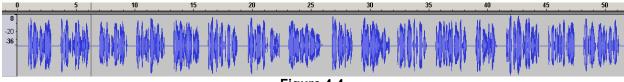
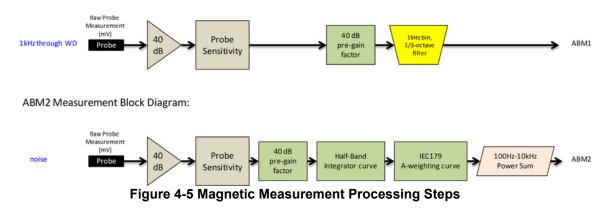


Figure 4-4 Temporal Characteristic of Normal Test Signal

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ABM1 Measurement Block Diagram:



IV. Test Procedure

- 1. Ambient Noise Check per C63.19 §7.3.1
 - a. Ambient interference was monitored using a Real-Time Analyzer between 100-10,000 Hz with 1/3 octave filtering.
 - b. "A-weighting" and Half-Band Integration was applied to the measurements.
 - c. Since this measurement was measured in the same method as ABM2 measurements, this level was verified to be more than 10 dB below the lowest measurement signal (which is the highest ABM2 measurement for a T4 WD). Therefore the maximum noise level for a T4 WD with an ABM1 = -18 dBA/m is: -18 - 30 - 10= -58 dBA/m
- 2. Measurement System Validation(See Figure 4-1)
 - a. The measurement system including the probe, pre-amplifier and acquisition system were validated as an entire system to ensure the reliability of test measurements.
 - b. ABM1 Validation

The magnetic field at the center of the Helmholtz coil is given by the equation (per C63.19 Annex D.10.1):

$$H_{c} = \frac{NI}{r\sqrt{1.25^{3}}} = \frac{N(\frac{V}{R})}{r\sqrt{1.25^{3}}}$$

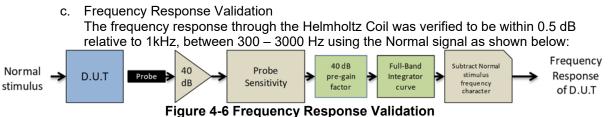
Where H_c = magnetic field strength in amperes per meter N = number of turns per coil

For the Helmholtz Coil, N=20; r=0.08m; R=10.2Ω and using V=18mV:

$$H_c = \frac{20 \cdot (\frac{0.018}{10.2})}{0.08 \cdot \sqrt{1.25^3}} = 0.316A/m \approx -10dB(A/m)$$

Therefore a pure tone of 1kHz was applied into the coils such that 18mV was observed across the resistor. The voltmeter used for measurement was verified to be capable of measurements in the audio band range. This theoretically generates an expected field of -10 dB(A/m) in the center of the Helmholtz coil which was used to validate the probe measurement at -10dB(A/m). This was verified to be within \pm 0.5 dB of the -10dB(A/m) value (see Page 18).

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d. ABM2 Measurement Validation

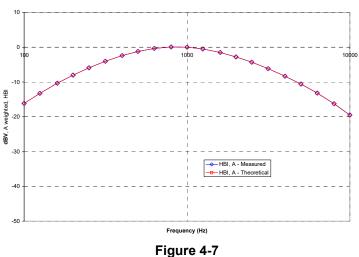
WD noise measurements are filtered with A-weighting and Half-Band Integration over a frequency range of 100Hz – 10kHz to process ABM2 measurements. Below is the verification of the system processing A-weighting and Half-Band integration between system input to output within 0.5 dB of the theoretical result:

ABM2 Frequency Response Validation					
	HBI, A -	HBI, A -			
f (Hz)	Measured	Theoretical	dB Var.		
	(dB re 1kHz)	(dB re 1kHz)			
100	-16.180	-16.170	-0.010		
125	-13.257	-13.250	-0.007		
160	-10.347	-10.340	-0.007		
200	-8.017	-8.010	-0.007		
250	-5.925	-5.920	-0.005		
315	-4.045	-4.040	-0.005		
400	-2.405	-2.400	-0.005		
500	-1.212	-1.210	-0.002		
630	-0.349	-0.350	0.001		
800	0.071	0.070	0.001		
1000	0.000	0.000	0.000		
1250	-0.503	-0.500	-0.003		
1600	-1.513	-1.510	-0.003		
2000	-2.778	-2.780	0.002		
2500	-4.316	-4.320	0.004		
3150	-6.166	-6.170	0.004		
4000	-8.322	-8.330	0.008		
5000	-10.573	-10.590	0.017		
6300	-13.178	-13.200	0.022		
8000	-16.241	-16.270	0.029		
10000	-19.495	-19.520	0.025		

Table 4-1 BM2 Frequency Response Validation

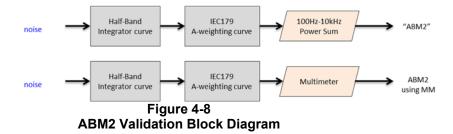
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ABM2 Frequency Response Validation

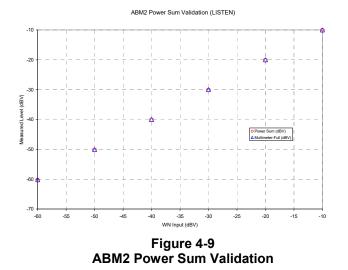
The ABM2 result is a power sum from 100Hz to 10kHz with half-band integration and Aweighting. To verify the power sum measurement, a power sum over the full band was measured and verified to track with the source level (See Figure 4-8). Therefore the setup in this step was used to verify the power sum post-processing for ABM2 measurements. See below block diagram:



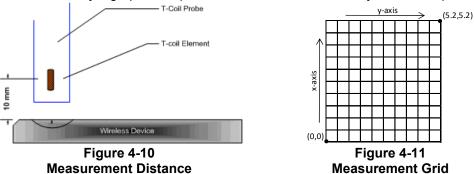
The power summed output results for a known input were compared to the multi-meter results to verify any deviation in the post-processing implemented with the power-sum.

Table 4-2 ABM2 Power Sum Validation					
WN Input (dBV)	Power Sum (dBV)	Multimeter-Full (dBV)	Dev (dB)		
-60	-60.36	-60.2	0.16		
-50	-50.19	-50.13	0.06		
-40	-40.14	-40.03	0.11		
-30	-30.13	-30.01	0.12		
-20	-20.12	-20	0.12		
-10	-10.14	-10	0.14		

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- 3. Measurement Test Setup
 - a. Fine scan above the WD (TEM)
 - i. A multitone signal was applied to the handset such that the phone acoustic output was stable within 1dB over the probe settling time and with the acoustic output level at the C63.19 specified levels (below). The measurement step size was in 2 mm increments at a distance of 10 mm between the surface of the wireless device as shown below (note that in Figure 4-11, the grid is not to scale but merely a graphical representation of the coordinate system in use):



- ii. After scanning, the planar field maximum point was determined. The position of the probe was moved to this location to setup the test using the SoundCheck system.
- iii. These steps were repeated for all T-coil orientations (axial and radial) per Figure 4-14 after a T-coil orientation was fully measured with the SoundCheck system.
 b. Speech Signal Setup to Base Station Simulator
 - Speech Signal Setup to base Station Simulator
 - i. C63.19 Table 7-1 states audio reference input levels for various technologies:

Standard	Technology	Input Level (dBm0)
TIA/EIA/IS-2000	CDMA	-18
J-STD-007	GSM (217)	-16
T1/T1P1/3GPP	UMTS (WCDMA)	-16
iDEN™	TDMA (22 and 11 Hz)	-18

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- c. Real-Time Analyzer (RTA)
 - i. The Real-Time Analyzer was configured to analyze measurements using 1/3 Octave band weighted filtering.
- d. WD Radio Configuration Selection
 - i. The device was chosen to be tested in the worst-case ABM2 condition (see below for GSM):

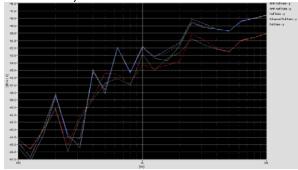
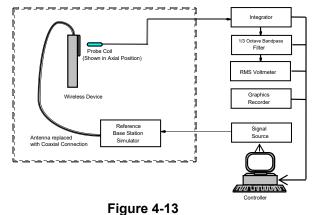


Figure 4-12 Vocoder Analysis for ABM Noise for GSM

- 4. Signal Quality Data Analysis
 - a. Narrow-band Magnetic Intensity
 - i. The standard specifies a 1kHz 1/3 octave band minimum field intensity for a sine tone. The ABM1 measurements were evaluated at 1kHz with 1/3 octave band filtering over an averaged period of 10 seconds.
 - b. Frequency Response
 - i. The appropriate frequency response curve was measured to curves in Figure 3-1 or Figure 3-2 between 300 3000 Hz using digital linear averaging (limit lines chosen according to measurement found in step 4a). A linear average over 3x the length of the artificial voice signal (3x sampling) was performed. A 10 second delay was configured in the measurement process of the stimulus to ensure handset vocoder latency effects and echo cancellation devices (if any) were appropriately stabilized during measurements.
 - ii. The appropriate post-processing was applied according to the system processing chain illustrated in Figure 4-6. All R10 frequencies were plotted with respect to 0dB at 1kHz value and aligned with respect to the EIA-504 mask.
 - iii. The margin is represented by the closest measured data point on the curve to the EIA-504 limit lines, in dB.
 - c. Signal Quality Index
 - i. Ensuring the WD was at maximum RF power, maximum volume, backlight off, display on, maximum contrast setting, keypad lights on (when possible) with no audio signal through the vocoder, the WD was measured over at least 100 Hz 10,000 Hz, maximized over 5 seconds with a 50ms sample time for the ABM2 measurement (5 second time period is used in noise measurements under standards such as IEEE 269, etc.).
 - ii. After applying half-band integration and A-weighting to the result, a power sum was applied over each 1/3 octave bandwidth frequency for an ABM2 value.
 - iii. This result was subtracted from the ABM1 result in step a, to obtain the Signal Quality.

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V. **Test Setup**



Audio Magnetic Field Test Setup

VI. **Deviation from C63.19 Test Procedure**

Non-conducted RF connection due to shielding effects of battery cover.

VII. Air Interface Technologies Tested

All air interfaces which support voice capabilities over a managed CMRS or pre-installed OTT VoIP applications were tested for T-coil unless otherwise noted. See Table 2-1 for more details regarding which modes were tested.

VIII. Wireless Device Channels and Frequencies

1. 2G/3G Modes

The frequencies listed in the table below are those that lie in the center of the bands used for cellular telephony. Low, middle and high channels were tested in each band for FCC compliance evaluation to ensure the maximum emission is captured across the entire band.

Center Channels and Frequencies						
Test frequencies & associated channels						
Channel	Frequency (MHz)					
Cellular 850						
190 (GSM)	836.60					
PCS 1900						
661 (GSM)	1880					

	Table 4-3						
Center C	hannels a	nd Freque	ncies				

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IX. Test Flow

The flow diagram below was followed (From C63.19):

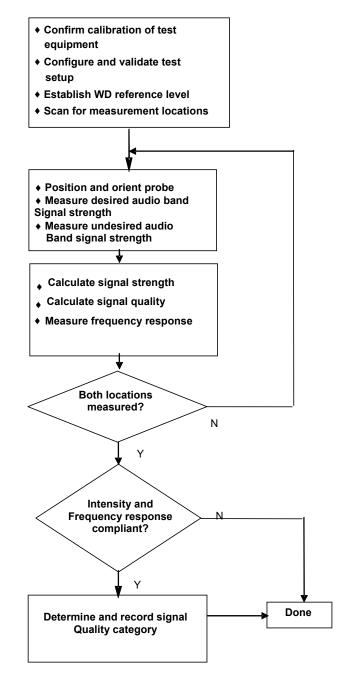


Figure 4-14 C63.19 T-Coil Signal Test Process

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5. T-COIL TEST SUMMARY

Table 5-1 Consolidated Tabled Results

		-	esponse rgin	e Magnetic FCC SNNR Intensity Verdict Verdict W		Margin from FCC			
C62 10 Section		8.3	3.2	8.:	3.1	8.3	3.4	Limit (dB)	Rating
C63.19 Section		Axial	Radial	Axial	Radial	Axial	Radial		
GSM	Cellular	PASS	NA	PASS	PASS	PASS	PASS	-9.21	Т3
GSW	PCS	PASS	NA	PASS	PASS	PASS	PASS	-9.21	15

I. Raw Handset Data

Table 5-2 Raw Data Results for GSM

Mode	Orientation	Channel	ABM1 [dB(A/m)]	ABM2 [dB(A/m)]	Ambient Noise [dB(A/m)]	Frequency Response Margin (dB)	S+N/N (dB)	FCC Limit (dB)	Margin from FCC Limit (dB)	C63.19-2011 Rating	Test Coordinates
		128	4.87	-24.61		1.98	29.48	20.00	-9.48	Т3	
	Axial	190	4.82	-24.39	-60.62	1.96	29.21	20.00	-9.21	Т3	2.6, 2.4
GSM850		251	4.86	-24.50		2.00	29.36	20.00	-9.36	T3	
G31050		128	-2.52	-38.60			36.08	20.00	-16.08	T4	
	Radial	190	-2.83	-38.06	-60.43	N/A	35.23	20.00	-15.23	T4	2.6, 1.6
		251	-2.54	-38.42			35.88	20.00	-15.88	T4	
		512	4.90	-30.62		1.97	35.52	20.00	-15.52	T4	
	Axial	661	5.06	-29.75	-60.62	1.97	34.81	20.00	-14.81	T4	2.6, 2.4
GSM1900		810	4.84	-29.94		1.96	34.78	20.00	-14.78	T4	
G3W1900		512	-2.49	-42.98			40.49	20.00	-20.49	T4	
	Radial	661	-2.50	-42.55	-60.43	N/A	40.05	20.00	-20.05	T4	2.6, 1.6
		810	-2.50	-42.54			40.04	20.00	-20.04	T4	

II. Test Notes

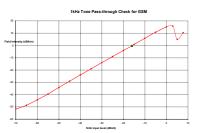
- A. General
 - 1. Phone Condition: Mute on; Backlight off; Max Volume; Max Contrast
 - 2. 'Radial' orientation refers to radial transverse.
 - 3. Hearing Aid Mode (**Phone→Call Settings→More Settings→Hearing aids**) was set to ON for Frequency Response compliance
 - 4. Speech Signal: 3GPP2 Normal Test Signal
 - 5. Bluetooth and WIFI were disabled for 2G modes while testing.
 - 6. The Margin from FCC limit column indicates a margin from the FCC limit for compliance (T3).

B. GSM

- 1. Power Configuration: GSM850: PCL=5, GSM1900: PCL=0;
- 2. Vocoder Configuration: EFR (GSM);

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III. 1 kHz Vocoder Application Check



This model was verified to be within the linear region for ABM1 measurements at -16 dBm0 for GSM. This measurement was taken in the axial configuration above the maximum location.

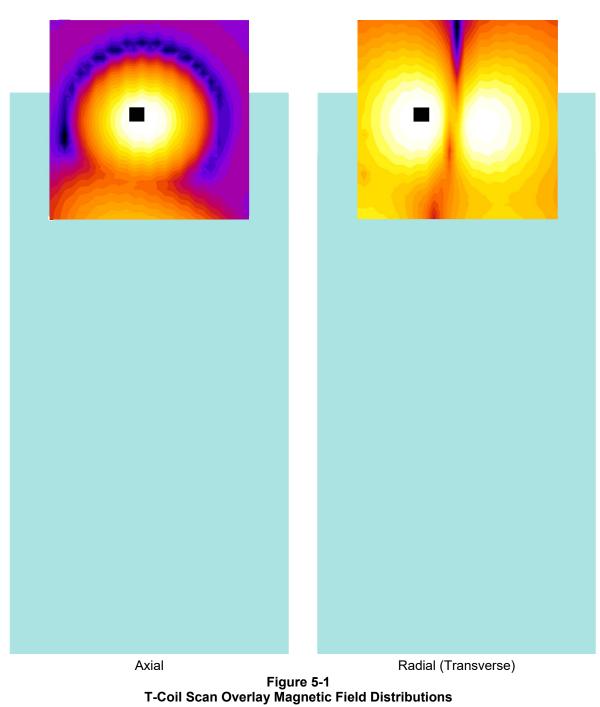
IV. T-Coil Validation Test Results

Item	Target	Result	Verdict
Axial	-		
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.191	PASS
Environmental Noise	< -58 dBA/m	-60.62	PASS
Frequency Response, from limits	> 0 dB	0.70	PASS
Radial			
Magnetic Intensity, -10 dBA/m	-10 ± 0.5 dB	-10.307	PASS
Environmental Noise	< -58 dBA/m	-60.43	PASS
Frequency Response, from limits	> 0 dB	0.70	PASS

Table 5-3 Helmholtz Coil Validation Table of Results – 04/08/2013

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Notes:

- 1. Final measurement locations are indicated by a cursor on the contour plots.
- 2. See Test Setup Photographs for actual WD overlay.

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6. MEASUREMENT UNCERTAINTY

Contribution	Data +/- %	Data +/- dB	Data Type	Probability distribution	Divisor	Standard uncertainty	Standard Uncertainty (dB)
ABM Noise	7.0%	0.29	Std. Dev.	Normal k=1	1.00	7.0%	
RF Reflections	4.7%	0.20	Specification	Rectangular	1.73	2.7%	
Reference Signal Level	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Positioning Accuracy	10.0%	0.41	Uncertainty	Rectangular	1.73	5.8%	
Probe Coil Sensitivity	12.2%	0.50	Specification	Rectangular	1.73	7.0%	
Probe Linearity	2.4%	0.10	Std. Dev.	Normal k=1	1.00	2.4%	
Cable Loss	2.8%	0.12	Specification	Rectangular	1.73	1.6%	
Frequency Analyzer	5.0%	0.21	Specification	Rectangular	1.73	2.9%	
System Repeatability	5.0%	0.21	Std. Dev.	Normal k=1	1.00	5.0%	
WD Repeatability	9.0%	0.37	Std. Dev.	Normal k=1	1.00	9.0%	
Positioner Accuracy	1.0%	0.04	Specification	Rectangular	1.73	0.6%	
Combined standard uncertainty, uc (k=1)							0.71
Expanded uncertainty (k=2),	95% conf	idence lev	/el			35.3%	1.31

Table 6-1 Uncertainty Estimation Table

Notes:

1. Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297.

2. All equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81 and NIST Tech Note 1297 and UKAS M3003.

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid compatibility tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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7. EQUIPMENT LIST

Table 7-1 Equipment List

		=4b				
Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Dell	Latitude E6540	SoundCheck Acoustic Analyzer Laptop	4/11/2017	Annual	4/11/2018	7BFNM32
Listen	SoundConnect	Microphone Power Supply	N/A		N/A	0899-PS150
Listen	SoundConnect	Microphone Power Supply	12/2/2016	Biennial	12/2/2018	PS2612
RME	Fireface UC	Soundcheck Acoustic Analyzer External Audio Interface	4/11/2017	Annual	4/11/2018	23528889
Rohde & Schwarz	CMW500	Wideband Radio Communication Tester	1/19/2018	Annual	1/19/2019	162125
Seekonk	NC-100	Torque Wrench (8" lb)	9/1/2016	Biennial	9/1/2018	21053
TEM	C63.19	Helmholtz Coil	12/7/2016	Biennial	12/7/2018	925
TEM	Radial T-Coil Probe	Radial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1130
TEM	Axial T-Coil Probe	Axial T-Coil Probe	12/7/2016	Biennial	12/7/2018	TEM-1124
TEM		HAC System Controller with Software	N/A		N/A	N/A
TEM		HAC Positioner	N/A		N/A	N/A

FCC ID: A3LSMJ337T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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8. TEST DATA

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01/11/2018

4/8/2018



DUT: HH Coil – SN: 925

Type: HH Coil Serial: 925

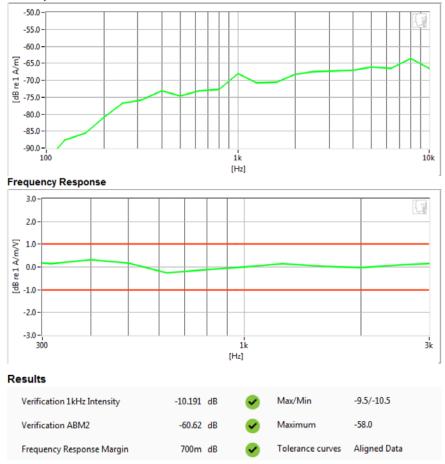
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

• Helmholtz Coil – SN: 925; Calibrated: 12/07/2016

Noise Spectrum



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FCC ID: A3LSMJ337T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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4/8/2018



DUT: HH Coil – SN: 925

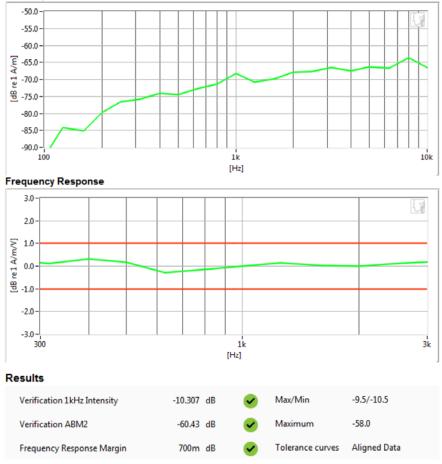
Type: HH Coil Serial: 925

Measurement Standard: ANSI C63.19-2011

Equipment:

- Probe: Radial T-Coil Probe SN: TEM-1130; Calibrated: 12/07/2016
- Helmholtz Coil SN: 925; Calibrated: 12/07/2016

Noise Spectrum



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PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337T

Type: Portable Handset Serial: 11912

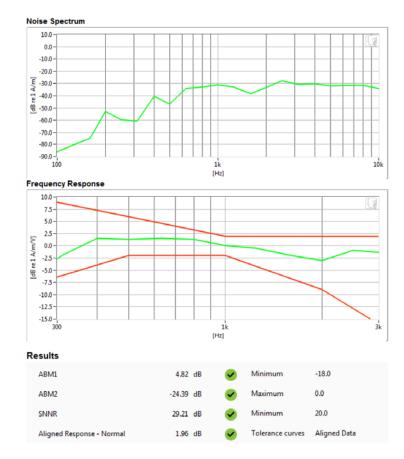
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

Test Configuration:

- Mode: GSM850
- Channel: 190
- Speech Signal: 3GPP2 Normal Test Signal



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PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337T

Type: Portable Handset Serial: 11912

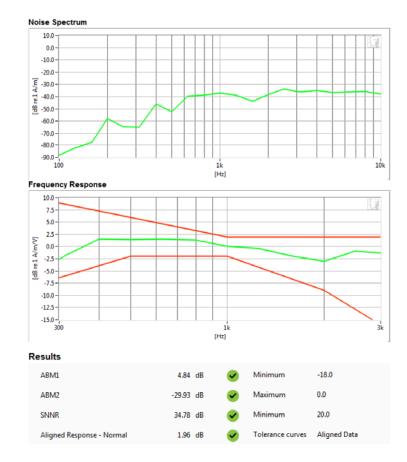
Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Axial T-Coil Probe – SN: TEM-1124; Calibrated: 12/07/2016

Test Configuration:

- Mode: GSM1900
- Channel: 810
- Speech Signal: 3GPP2 Normal Test Signal



PCTEST 2018

FCC ID: A3LSMJ337T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337T

Type: Portable Handset Serial: 11912

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

Test Configuration:

- Mode: GSM850
- Channel: 190

Noise Spectrum



PCTEST 2018

FCC ID: A3LSMJ337T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager
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				01/11/2018



PCTEST Hearing-Aid Compatibility Facility

DUT: A3LSMJ337T

Type: Portable Handset Serial: 11912

Measurement Standard: ANSI C63.19-2011

Equipment:

Probe: Radial T-Coil Probe – SN: TEM-1130; Calibrated: 12/07/2016

Test Configuration:

- Mode: GSM1900
- Channel: 810

Noise Spectrum



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9. CALIBRATION CERTIFICATES

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01/11/2018

West (Caldwell Calibrati	on Laboratories Inc.	
Certi	ficate of	Calibration	
	AXIAL T COIL Manufactured by: Model No: Serial No:	PROBE TEM CONSULTING AXIAL T COIL PROBE TEM-1124	
	Calibration Recall No:	27068	
	Submitted	l By:	
	Customer: ANDR	REW HARWELL	e
	Address: 6660-1	ST ENGINEERING LAB 3 DOBBIN ROAD IMBIA MD 21045	
National Institute of S This document certifi submitter.	Standards and Technology or to es that the instrument met the fo	d specification using standards traceable to the accepted values of natural physical constants. Mowing specification upon its return to the	
	ation Laboratories Procedure N bration, the instrument was four	at to be:	
Within		o. ANAL TO TEMPO nd to be: 12/29/2016	(A)
tolerance of the indic	ated specification. See attached	Report of Calibration.	
West Caldwell Calibr requirements, ISO 10 and ISO 17025	ation Laboratories' calibration (012-1 MIL STD 45662A, ANSI/	control system meets the following NCSL Z540-1, IEC Guide 25, ISO 9001:2008	
Note: With this Certificate	Report of Calibration is included.	Approved by:	e
Calibration Date:	07-Dec-16	FC	
Certificate No:	27068 - 3	Felix Christopher (QA Mgr.)	旚
QA Doc. #1051 Rev. 2.0 10/1/01	Certificate Page		
41	Vest Caldwell		
Λ.	Calibration		

FCC ID: A3LSMJ337T		HAC (T-COIL) TEST REPORT	SAMSUNG	Approved by: Quality Manager	
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HCATEMC_TEM 1124_Dec-07-2016





1575 State Route 96, Victor NY 14564

ACCREDITED Calibration Lab. Cort. # 1533.01

REPORT OF CALIBRATION

TEM Consulting LP Axial T Coil Probe		for Model No.: Axia	Serial No.: TEM 1124			
Company : PCTEST Engineering Lab.				I. D. No	: 80578	
bration results.			_			
	ty measured wit	h Heimheit	z Coll			×
the number of tur	Helmholtz Coil;	10	N	Batora & atte	er data same	·: A
the radius of each	r	10 0.204	No.	Laboratory Environ		
the current in the coi	, ,	0.09	A	Laboratory Environ Ambient Temperature:	20.2	°C
	Coil Constant:	7.09	A/m/V	Ambient Humidity:	31.4	% RH
Helmholtz Coil		5.98	A/m	Ambient Pressure:	99.1	*Pa
Heimilola Gon	magneac neia,	3.50	7-1 m		7-D16	kra
-	-			Calibration Date:	7-000-10	
Probe	Sensitivity at	1000	Hz. ⊿BV/A/m		07000	-3
	WEB	-60.23 0.974	a B V/A/ m m V/A/ m	Report Number: Control Number:	27068 27068	-3
P	be resistance	904	m V////m Ohme	Control Number:	27000	
e above listed instrum				urarle enacifications		
Calibration is traceable through			683/284413-14	urer's specifications.		
	NICI test number:	\$.	003/204413-14			
	n: 0.30dB at 05% o	onfidence leve	al with a coverage factor of k	k=7		
expanded uncertainty of calibratio		onfidence leve	el with a co∨erage factor of k	k=2.		
expanded uncertainty of calibratio		onfidence leve		k=2.		
expanded uncertainty of calibratio		onfidence leve	el with a coverage factor of k Axial Probe Response		ed Probe Resp.	
expanded uncertainty of calibratio		onfidence leve			ed Probe Resp.	
expanded uncertainty of calibratio		onfidence leve			ed Probe Resp.	
20 15		onfidence leve			ed Probe Resp.	
expanded uncertainty of calibratio		onfidence leve			ed Probe Resp.	
20 15 10		onfidence leve			ed Probe Resp.	
20 15 10					ed Probe Resp.	
20 15 10					ed Probe Resp.	
20 15 0 0 0 0 0 0 0 0 0 0 0 0 0		onfidence leve			ed Probe Resp.	
20 15 10		onfidence leve			ed Probe Resp.	
20 15 10					ed Probe Resp.	
expanded uncertainty of calibratio					ed Probe Resp.	
expanded uncertainty of calibratio					ed Probe Resp.	
expanded uncertainty of calibratio		onfidence leve			ed Probe Resp.	
expanded uncertainty of calibratio					ed Probe Resp.	100

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016	Measurements performed by: FC	
Calibrated on WCCL system type 9700	Felix Christopher	
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HCATEMC_TEM 1124_Dec-07-2016

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Vieter NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Axial T Coil Probe

Model No.: Axial T Coil Probe

Serial No.: TEM 1124

Company : PCTEST Engineering Lab.

Test	Function	Tolera	nce	Measured values			
				Before	Out	Remarks	
1.0	Probe Sensitivity at	1000 Hz.	d BV/A/m	-60.23			
2.0	Prabe Lovel Lineerity	Ror. (0 d B)	⊌B 6 0 -6 -12	6.03 0.00 -6.03 -12.05			
3.0	Probe Frequency Response	Rr. (0 d B)	H₂ 100 126 158 200 251 316 398 501 631 794 1000 1259 1585 1995 2512 3162 3981 5012 6310 7943 10000	-19.8 -18.0 -16.0 -13.9 -12.0 -9.9 -8.0 -6.0 -4.0 -2.0 0.0 2.0 4.0 6.0 7.9 9.9 11.9 13.9 15.9 18.0 20.2			

Instruments used for celibration:			Date of Cal.	Tracespility No.	Due Dete
HP	34401A	S/N 36064102	1-Oct-2016	,287708	1-Oct-2017
HP	34401A	S/N 36102471	1-Oet-2016	,287708	1-Oct-2017
HP	33120A	S/N 36043716	1-Oct-2016	.287708	1-Oct-2017
B&K	2133	S/N 1583254	1-Oct-2016	683/284413-14	1-Oat-2017

Cal. Date: 7-Dac-2016

Calibrated on WCCL system type 9700

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Tested by: Felix Christopher

R.v. 7.0 Jan. 24, 2014 Dev. # 1038 HCATEMC

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West	Caldwell Cal	ibration I	aborator	ies Inc.	
Cert	ificate	of Ca	alibr	ation	
	RADIA) Manufactured 1 Model No: Serial No: Calibration Rec	RA TE	M CONSULTIN DIAL T COIL PI M-1130		
		Submitted By:			
	Customer:	ANDREW HA	ARWELL		
	Company: Address:	PCTEST ENG 6660-B DOBH COLUMBIA	GINEERING LA BIN ROAD	B MD 21045	
National Institute of	ent was calibrated to the Standards and Technol ies that the instrument i	ogy or to accepte	d values of natur	al physical constants	10 }.
West Caldwell Calib	ration Laboratories Pro	cedure No.	RADIAL T TEM C	Insal	
Upon receipt for Cali	ibration, the instrument	was found to be	:	VQSA 12/29/2016	
Withi	n (X)			1421/2010	
tolerance of the indi	cated specification. See	attached Report	of Calibration.		
West Caldwell Calibo requirements, ISO 10 and ISO 17025	ration Laboratories' cal 0012-1 MIL STD 45662.	ibration control A, ANSI/NCSL Z	system meets the 540-1, IEC Guid	following e 25, ISO 9001:2008	
Note: With this Certificate	e, Report of Calibration is in	cluded.	Approved b	y:	
Calibration Date:	07-Dec-16			FC	
Certificate No:	27068 - ²		Felix Chris	topher (QA Mgr.)	_
QA Doc. #1051 Rev. 2.0 10/1/01		cate Page 1 of 1		C 17025:2005	
Л	West Caldwell Calibration				
	~~	Inc.		REDITED	

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HCRTEMC_TEM-1130_Dec-07-2016





1575 State Route 96, Victor NY 14564

Callbration Lab. Cort. # 1533.01

REPORT OF CALIBRATION

TEM Consulting LP Radial T Coil Probe		for Model No.: Radia	al T Coil Probe	Serial No.:	TEM-1130
Company : PCTEST Engineering Lab.				I. D. No:	80579
ration results.					
Probe Sensitivity measured wit	h Heimhei	z Coll			v
Helmholtz Coil;			Bafora & att	er data samai	X
the number of turns on each coil;	10	Ne.			
the radius of each coil, in meters;	0.204 0.09	m A	Laboratory Environ		°C
the current in the coils, in amperes.;			Ambient Temperature:	20.2	-
Helmholtz Coil Constant;	7.09	A/m/V	Ambient Humidity!	31.4	% RH
Helmholtz Coil magnetic field;	5.98	A/m	Ambient Pressure:	99.1	кРа
			Calibration Date:	7-D16	
Probe Sensitivity at	1000	Hz.			
Was	-60.27	⊿BV/A/m	Report Number:	27068	-2
	0.969	m V/A/m	Control Number:	27068	
Probe resistance	902	Ohm.			
above listed instrument meets or o	exceeds fl		rer's specifications.		
Calibration is traceable through NIST test number		683/284413-14	i er o opeennemennonon		
expanded uncertainty of calibration: 0.30dB at 95% c			2.		
h represents Probes Frequency Response.					
		Radial Probe Response			
20		radia riobo responso	Measur	ed Probe Resp.	
20					
15				-	
10					+ + + -
5					
0					
-5					+ $+$ $+$ $+$ $+$ $+$ $+$ $+$ $+$ $+$
10					
15					
20					
	Fre	eq. (Hz) 1000			1000
100					
above listed instrument was checked us bration Laboratories Inc. procedure :			ented in West Caldwell Rev. 7.0 Jan. 24, 2014		

intended to implement the requirements of ISO10012-1, IEC Guide 25, ANSI/NCSL Z540-1, (MIL-STD-45662A) and ISO 9001:2008, ISO 17025

Cal. Date: 7-Dec-2016	Measurements performed by: FC
Calibrated on WCCL system type 9700	Felix Christopher
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HCRTEMC_TEM-1130_Dec-07-2016

West Caldwell Calibration Laboratories Inc.

1575 State Route 96, Vieter NY 14564 Tel. (585) 586-3900 FAX (585) 586-4327

Calibration Data Record

TEM Consulting LP Radial T Coil Probe

Model No.: Radial T Coil Probe

Serial No.: TEM-1130

Company : PCTEST Engineering Lab.

Test	Function	Tolera	Tolerance		Measured values		
				Before	Out	Remarks	
1.0	Probe Sensitivity at	1000 Hz.	a BV/A/m	-60.27			
2.0	Prabe Levei Linearity	R•f. (0 dB)	⊿ B 6 0 -6 -12	6.03 0.00 -6.03 -12.06			
3.0	Probe Frequency Reeponee	Rr. (0 d B)	H₂ 100 126 158 200 251 316 398 501 631 794 1000 1259 1585 1995 2512 3162 3981 5012 6310 7943 10000	-19.9 -18.0 -16.0 -13.9 -12.0 -8.0 -6.0 -4.0 -2.0 0.0 2.0 4.0 6.0 7.9 9.9 11.9 13.9 15.9 18.0 20.2			

Instruments used for celibration:			Date of Cal.	Tracesbility No.	Due Dete
HP	34401A	S/N 36064102	1-Oct-2016	,287708	1-Oct-2017
HP	34401A	S/N 36102471	1-Oet-2016	,287708	1-Oct-2017
HP	33120A	S/N 36043716	1-Oct-2016	.287708	1-0ct-2017
B&K	2133	S/N 1583254	1-Oat-2016	683/284413-14	1-Oct-2017

Cal. Date: 7-Dac-2016

Calibrated on WCCL system type 9700

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Tested by: Felix Christopher

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10. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI C63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

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